Search Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/616,650	AOKI ET AL.	
Examiner	Art Unit	
KEVIN L. LEE	3753	

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Class	Subclass	Date	Examiner		
UPDATED	SEARCH	1/18/2006	KL		
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Subclass		
	Date	Examiner

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
INTERFERENCE search (US-PGPUB)	1/18/2006	KL